ARMI MBH

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ISO

17034:2016

Certificate of Analysis

ISO/IEC

17025:2017

Revision No.: 000

Revision Date: 04/17/2023

15

ISO

9001:2015

Product ID: IARM-NIB2-23

Certified Reference Material

Product Description: Nickel Hastelloy B-2 / UNS N10665

Description and Intended Use: This Certified Reference Material is covered under the scope of accreditation to ISO 17034 by LGC Standards - Manchester, NH. As an ISO 17034 certified reference material, appropriate use of this material will fulfill the certified reference material and traceability requirements for use in ISO 17025 accredited laboratories. This CRM may come in the form of a solid disk, or chips. The intended use of this CRM may include, but is not limited to, the calibration of instruments and the validation of analytical methods.

				Certi	ied Values	s listed in	wt.% with a	ssociated u	ncertainties					
	AI	0.13	±0.02	Cr	0.579	±0.009	9 M o	o 27.1	±0.2	Т	i 0.0	21	±0.001	
	В	0.0018	±0.0002	Fe	1.36	±0.02	Ν	0.0007	±0.0002	V	V 0.004	42	± 0.000	7
	С	0.0030	±0.0003	Mg	0.0012	±0.00	04 Ni	70.2	±0.2					
	Co	0.116	±0.006	Mn	0.504	±0.00	9 S	0.0007	±0.0004					
Indicative Values listed in ppm														
Cu	38	H 2	Nb	14 C) 13	P 3	6 Si	667	Sn 9	Та	25	V	50	Zr

Homogeneity and Uncertainty: "Uncertainty" values, as reported adjacent to certified concentration values, are based on a 95% Confidence Interval. These estimated uncertainties include the combined effects of method imprecision, material inhomogeneity, and any bias between methods. Homogeneity data from experimental XRF results are reflected in both the overall statistics and certified data. Homogeneity samples are selected by a systematic sampling procedure. The number of samples may be determined by equation 1, where Nprod is the number of units produced and Nmin is the number of samples used for homogeneity testing. These samples are arranged in a simple randomized design such that each sample is analyzed multiple times by XRF. Homogeneity may also be determined within sample using an applied version of ASTM E826. A single factor ANOVA is used to calculated uncertainty due to inhomogeneity (Uhom). Uncertainty of the material is calculated by equation 2, where H=Uhom, S= Standard deviation, t= t-value at 95% CI, and n= number of observations.

$$1.N_{MIN} = \max(10, \sqrt[3]{N_{PROD}})$$

$$2.U_{CRM} = \frac{\sqrt{H^2 + S^2}}{\sqrt{n}} * t$$

Certification Laboratories: Much of the analytical work performed to assess this material has been carried out by laboratories with proven competence, as indicated by their accreditation to ISO 17025. It is an implicit requirement for this accreditation that analytical work should be performed with due traceability, via an unbroken chain of comparisons, each with stated uncertainty, to primary standards such as the mole, or to nationally- or internationally-recognised reference materials. Of the individual results herein, some have traceability (to the mole) via primary analytical methods. Some are traceable to substances of known stoichiometry. Most have traceability via commercial solutions. Furthermore, some results have additional traceability to NIST standards, as part of the analytical calibration or process control.

- Anderson Laboratories, Inc. Greendale, WI Applied Technical Services - Marietta, GA
 - - Laboratory Testing, Inc. Hatfield, PA
 - Dirats Laboratories Westfield, MA
- EAG Laboratories Liverpool, NY
- Elemental Analysis Inc. Lexington, KY
- IMR Test Labs Lansing, NY
- LGC Standards Manchester, NH
- New Hampshire Materials Laboratory Inc Somersworth, NH
- NSL Analytical Services Cleveland, OH
- Scrooby's Laboratory Service Pty Ltd Benoni, South Africa
- SGS MSi Melrose Park, IL Sheffield Assay Office - Sheffield, England
- TEC Eurolab Campogalliano, Italy

Instructions for Use: The test surface is on the opposite side of the labeled surface, which includes the material identification. The entire thickness of the unit is certified. However, the user is cautioned not to measure disks less than 2 mm thick when using X-ray fluorescence spectrometry. Each packaged disk has been prepared by finishing the test surface using a lathe. The user must determine the correct surface preparation procedure for each analytical technique. The user is cautioned to use care when either resurfacing the disk or performing additional polishing, as these processes may contaminate the surface. The minimum sample size for chips should be individually evaluated based on the analytical technique used; this would typically be greater than 0.1 grams. The material should be stored in a cool, dry location when not in use.

Chips are not recommended for gas analysis.

Period of Validity: The certification of this material is valid indefinitely, within the uncertainty specified, provided the material is handled and stored in accordance with the instructions stated on this certificate. The certification is nullified if the material is damaged, contaminated, otherwise modified, or used in a manner for which it was not intended.

Chuck Goudreau, Certifying Officer

April 17, 2023 Certification Date



ISO 17034 Accredited: Reference Materials Producer, Certificate # 2848.02 ISO/IEC 17025 Accredited: Chemical Testing, Certificate # 2848.01

Conditions of Sale and Supply: All CRMs & RMs sold are subject to applicable LGC Standard Terms and Conditions of Sale.



The following data represents all pertinent information reported as it applies to the chemical characterization of this material.

	Al	В	С	Co	Cr	Cu	Fe	Н	Mg	N	In	Мо	N	Nb
1	0.0750	0.0014	0.0020	0.0960	0.5460	0.0026	1.2700	0.0002	0.0005		600	26.4400	0.0003	0.0003
2	0.0730	0.0014	0.0020	0.1093	0.5400	0.0020	1.3060	0.0002	0.0000		810	26.5440	0.0003	0.0005
3	0.0905	0.0015	0.0024	0.11035	0.5650	0.0020	1.3170		0.0012	-	870	26.8780	0.0004	0.0003
4	0.0903	0.0016	0.0025	0.1101	0.5654	0.0031	1.3210		0.0012	-	899	26.9000	0.0006	0.0014
5	0.0330	0.0010	0.0020	0.1140	0.5667	0.0032	1.3260		0.0012		900	26.9067	0.0007	0.0020
	0.1210	0.0017	0.0029		0.5670	0.0033	1.3290				900	26.9520		
6				0.1180					0.0015				0.0008	< 0.0005
7	0.1300	0.0020	0.0029	0.1187	0.5700	0.0035	1.3626		0.0019		900	26.9890	0.0008	< 0.0020
8	0.1300	0.0020	0.0030	0.1197	0.5710	0.0035	1.3660		< 0.000		919	27.1400	0.0008	< 0.005
9	0.1540	0.0020	0.0031	0.1230	0.5726	0.0050	1.3730		< 0.005		030	27.1600	0.0010	< 0.005
10	0.1543	0.0021	0.0032	0.1240	0.5780	0.0050	1.3810		< 0.005		030	27.1920	0.0012	<0.01
11	0.1569	0.0022	0.0033	0.1243	0.5800	0.0051	1.3831		< 0.005		040	27.2200	<0.0010	
12	0.1587	< 0.005	0.0035		0.5838	0.0053	1.3860		< 0.005		070	27.2800		
13	0.1600	<0.005	0.0043		0.5842	<0.005	1.3870		<0.01		127	27.3300		
14	0.1630	<0.01			0.5900	<0.01	1.3980		<0.01		129	27.4000		
15	0.1740	<0.01			0.5934		1.4037				150	27.4830		
16					0.5960		1.4510				150	27.5000		
17					0.5990						179	27.5112		
18					0.6290						240			
19										0.5	300			
20											460			
Mean	0.1312	0.0018	0.0030	0.1158	0.5789	0.0038	1.3600	0.0002	0.0012		035	27.1074	0.0007	0.0014
STDV	0.0326	0.0003	0.0006	0.0083	0.0184	0.0010	0.0453		0.0004		194	0.3146	0.0003	0.0011
Certified	0.13	0.0018	0.0030	0.116	0.579	(0.0038)	1.36	(0.0002)	0.0012		504	27.1	0.0007	(0.0014)
UCRM	0.02	0.0002	0.0003	0.006	0.009	(010000)	0.02	(*****=)	0.0004		009	0.2	0.0002	(0.000.1)
Methods	IM,I,G,O,>		C,G	IM,I,O,X	I,O,X	IM,I,O	I,G,O,X	F	IM,I,O,		,0,X	I,O,X	F	IM,O,I
motrodo	,1,0,0,0	(111,1,0	0,0	111,1,0,70	1,0,71	,	1,0,0,7		111,1,0,	1,0	0,70	1,0,7		111,0,1
	Ni	0	Р	S	Si	Sn	Та	Ti		V	W	Zr		
1	69.5200	0.0006	0.0005	0.0002	0.0062	0.0003	0.000			0002	0.003			
2	69.6500	0.0000	0.0003	0.0002	0.0002	0.0003	0.000			002	0.003			
3	69.8500	0.0010	0.0030	0.0005	0.0034	0.0004	0.001			002	0.003			
4	69.8730	0.0023	0.0036	0.0005	0.0130	0.0000	0.002			002	0.003			
5	69.9320		0.0030	0.0000	0.0144	< 0.0022				0008	0.003			
6	69.9773		0.0049	0.0011	0.0190	< 0.0001	< 0.00			047	0.004			
1	70.0060		0.0052	0.0011	0.0232	< 0.0010				066	0.005			
8	70.3000		0.0060	< 0.0002	0.0948	< 0.002	< 0.00			083	0.005			
9	70.3100		< 0.0050	< 0.001	0.0981	< 0.002	< 0.00			106	0.005			
10	70.3400		< 0.0050	< 0.001	0.1000	< 0.002	< 0.00			005	< 0.000		-	
11	70.4000		<0.01	< 0.001	0.1000	< 0.005	< 0.00			.005	< 0.00		-	
12	70.4033			<0.0010	0.1012	< 0.005	< 0.00			.005	< 0.01			
13	70.4100				0.1100	< 0.01	< 0.0).01	<0.01			
14	70.6000			L	0.1284	<0.01	<0.0).01		<0.0		
15	70.7700				0.1660		_	0.024		0.01		<0.0	05	
16					< 0.01		_	0.025						
17					<0.01			<0.0						
18					<0.05			<0.0	1					
19														
20														
Mean	70.1561	0.0013	0.0036	0.0007	0.0667	0.0009	0.002	5 0.020	0.0	0050	0.004	2 0.00	15	
STDV	0.3562	0.0009	0.0020	0.0004	0.0534	0.0009	0.001			0054	0.000			
Certified	70.2	(0.0013)	(0.0036)	0.0007	(0.0667)	(0.0009)	(0.002)050)	0.004			
	0.2	(0.0010)	(0.0000)	0.0001	(0.0001)	(0.0000)	10.002	0.02			0.001	1	· •/	

Legend: W = Classical, C = Combustion, F = Fusion, A = AA or GFAA, I = ICP or DCP, IM=ICP-MS, D = DC Arc, O = AES, X = XRF, G = GDAES or GDMS, H = Hollow Cathode AES

I,IM,O,X

I,IM,O,X

0.001

IM,I,X,O

IM,I,X

0.0007

IM,I

IM,I,O,X

0.0004

IM,I,O,X

C,G

O,I,IM,X

F



UCRM Methods 0.2

I,G,O,X